

Hydrogen Peroxide, 30%
CMOS
(Stabilized)



Material No.: 2190-23
Batch No.: 24F2861006
Manufactured Date: 2024-06-27
Expiration Date: 2025-12-26
Revision No.: 0

Certificate of Analysis

Test	Specification	Result
Assay (H ₂ O ₂)	30.0 – 32.0 %	31.6 %
Color (APHA)	≤ 10	5
Free Acid (µeq/g)	≤ 0.2	0.1
Residue after Evaporation	≤ 10 ppm	2 ppm
Ammonium (NH ₄)	≤ 3 ppm	< 3 ppm
Chloride (Cl)	≤ 0.2 ppm	< 0.2 ppm
Nitrate (NO ₃)	≤ 2 ppm	< 2 ppm
Phosphate (PO ₄)	≤ 1 ppm	1 ppm
Sulfate (SO ₄)	≤ 3 ppm	< 3 ppm
Trace Impurities – Aluminum (Al)	≤ 70.0 ppb	11.3 ppb
Arsenic and Antimony (as As)	≤ 10.0 ppb	< 10.0 ppb
Trace Impurities – Barium (Ba)	≤ 20.0 ppb	< 1.0 ppb
Trace Impurities – Beryllium (Be)	≤ 10.0 ppb	< 1.0 ppb
Trace Impurities – Bismuth (Bi)	≤ 20.0 ppb	< 10.0 ppb
Trace Impurities – Boron (B)	≤ 10.0 ppb	< 5.0 ppb
Trace Impurities – Cadmium (Cd)	≤ 10.0 ppb	< 1.0 ppb
Trace Impurities – Calcium (Ca)	≤ 50.0 ppb	< 1.0 ppb
Trace Impurities – Chromium (Cr)	≤ 20.0 ppb	2.4 ppb
Trace Impurities – Cobalt (Co)	≤ 10.0 ppb	< 1.0 ppb
Trace Impurities – Copper (Cu)	≤ 10.0 ppb	< 1.0 ppb
Trace Impurities – Gallium (Ga)	≤ 20.0 ppb	< 1.0 ppb
Trace Impurities – Germanium (Ge)	≤ 10.0 ppb	< 10.0 ppb
Trace Impurities – Gold (Au)	≤ 10.0 ppb	< 5.0 ppb
Heavy Metals (as Pb)	≤ 500.0 ppb	< 250.0 ppb
Trace Impurities – Iron (Fe)	≤ 50.0 ppb	5.3 ppb
Trace Impurities – Lead (Pb)	≤ 10.0 ppb	< 10.0 ppb
Trace Impurities – Lithium (Li)	≤ 10.0 ppb	< 1.0 ppb
Trace Impurities – Magnesium (Mg)	≤ 10.0 ppb	< 1.0 ppb

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Trace Impurities – Manganese (Mn)	≤ 10.0 ppb	< 1.0 ppb
Trace Impurities – Molybdenum (Mo)	≤ 10.0 ppb	< 5.0 ppb
Trace Impurities – Nickel (Ni)	≤ 10.0 ppb	< 5.0 ppb
Trace Impurities – Niobium (Nb)	≤ 10.0 ppb	< 1.0 ppb
Trace Impurities – Potassium (K)	≤ 600.0 ppb	209.2 ppb
Trace Impurities – Silicon (Si)	≤ 100.0 ppb	< 10.0 ppb
Trace Impurities – Silver (Ag)	≤ 10.0 ppb	< 1.0 ppb
Trace Impurities – Sodium (Na)	≤ 100.0 ppb	< 5.0 ppb
Trace Impurities – Strontium (Sr)	≤ 10.0 ppb	< 1.0 ppb
Trace Impurities – Tantalum (Ta)	≤ 10.0 ppb	< 5.0 ppb
Trace Impurities – Thallium (Tl)	≤ 50.0 ppb	< 5.0 ppb
Trace Impurities – Tin (Sn)	190.0 – 500.0 ppb	330.8 ppb
Trace Impurities – Titanium (Ti)	≤ 10.0 ppb	< 1.0 ppb
Trace Impurities – Vanadium (V)	≤ 10.0 ppb	< 1.0 ppb
Trace Impurities – Zinc (Zn)	≤ 50 ppb	< 1 ppb
Trace Impurities – Zirconium (Zr)	≤ 10.0 ppb	< 1.0 ppb
Particle Count – 0.2 µm and greater	≤ 1175 par/ml	883 par/ml
Particle Count – 0.5 µm and greater	≤ 100 par/ml	25 par/ml

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For Microelectronic Use

Country of Origin: USA
Packaging Site: Paris Mfg Ctr & DC

Michelle Bales
Sr. Manager, Quality Assurance

For questions on this Certificate of Analysis please contact Technical Services at 855.282.6867 or +1.610.386.1700
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